

Form PTO-1449
(REV. 8-83)

US Dept. of Commerce
PATENT & TRADEMARK OFFICE

ATTY DOCKET NO.
119230

APPLICATION NO.
10/807,283

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANT(S)
Hirotuna MIURA

FILING DATE
March 24, 2004

GROUP
3611

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
REZ	1	JP-A-10-12377 (w/English abstract & JPO translation)	01/16/1998	Japan		
REZ	2	JP-A-2001-51296 (w/English abstract & JPO translation)	02/23/2001	Japan		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER

DATE CONSIDERED

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: June 29, 2004

Sheet 1 of 1Form PTO-1449
(REV. 1/06)US Dept. of Commerce
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U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name

FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
	1	KR-A-2003-0035759	05/15/2002	Korea		
REZ	2	JP-A-2000-338648	12/08/2000	Japan	X	X
REZ	3	JP-A-2001-196172	07/19/2001	Japan	X	X

OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER

DATE CONSIDERED
4/27/06

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: February 6, 2006